

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of  
Invention

DEFECT DIAGNOSIS FOR SEMICONDUCTOR INTEGRATED  
CIRCUITS

Application Number :

10/710,879

Confirmation Number:

First Named Applicant:

James Adklisson

Attorney Docket Number:

BUR920040092US1

Art Unit:

2825

Examiner:

TUYEN TO

Search string:

( 6636064 or 6605956 or 6566885 or 6524873 or 6347386 or 6308290 or 6185707  
or 5923533 or 4947357 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
TT	1	6636064	2003-10-21	Satya et al.			
TT	2	6605956	2003-08-12	Farnworth et al.			
TT	3	6566885	2003-05-20	Pinto et al.			
TT	4	6524873	2003-02-25	Satya et al.			
TT	5	6347386	2002-02-12	Beffa			
TT	6	6308290	2001-10-23	Forlenza et al.			
TT	7	6185707	2001-02-06	Smith et al.			
TT	8	5923533	1999-07-13	Yi			
TT	9	4947357	1990-08-07	Stewart et al.			

Signature

Tuyen To

Examiner Name

Date

TUYEN TO

01-30-2006